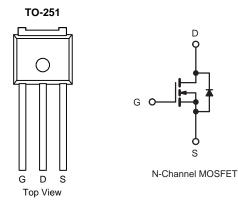


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)		
30	0.07 at V _{GS} = 10 V	53	19 nC		
30	0.09 at V_{GS} = 4.5 V	48	19110		



FEATURES

- Halogen-free
- TrenchFET[®] Gen III Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- DC/DC Conversion
 - System Power



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	V	
	T _C = 25 °C		53		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		41		
Continuous Drain Current $(T_j = 150^{\circ} C)$	T _A = 25 °C	I _D	14 ^{b, c}	^	
	T _A = 70 °C		10 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	165		
Avalanche Current	L = 0.1 mH	I _{AS}	25		
Avalanche Energy		E _{AS}	40	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C		15	Α	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.9 ^{b, c}	A	
	T _C = 25 °C		28		
Maximum Dawar Dissinction	T _C = 70 °C	Р	18	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.5 ^{b, c}	V V	
	T _A = 70 °C		2.2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	<u></u>	
Soldering Recommendations (Peak Tempera		260	U		

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient	t ≤ 10 s	R _{thJA}	29	36	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	3.6	4.5	0/11		

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

SPECIFICATIONS $T_J = 25 \text{ °C}$, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				_			
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		33		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- 10 - 200 μΛ		- 5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.2		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ $V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			1 5	μA	
On-State Drain Current ^a	I- 4 3	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	15		5	A	
	I _{D(on)}	$V_{\rm DS} = 3 \text{ V}, \text{ V}_{\rm GS} = 10 \text{ V}$ $V_{\rm GS} = 10 \text{ V}, \text{ I}_{\rm D} = 10 \text{ A}$	15	0.070		A	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 7 \text{ A}$				Ω	
Forward Transconductors		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 7 \text{ A}$ $V_{DS} = 15 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		0.090		6	
Forward Transconductance ^a	9 _{fs}	$v_{\rm DS} = 15$ V, $I_{\rm D} = 10$ A		24		S	
Dynamic ^b			r	1	1	1	
Input Capacitance	C _{iss}			1400		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		200			
Reverse Transfer Capacitance	C _{rss}			150			
Total Gate Charge	Qg	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$		33 18		nC	
Gate-Source Charge	Q _{gs}	V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 10 A		7.3			
Gate-Drain Charge	Q _{gd}			6.2			
Gate Resistance	R _g	f = 1 MHz	0.2	0.8	1.6	Ω	
Turn-On Delay Time	t _{d(on)}			15	30		
Rise Time	t _r	- V _{DD} = 15 V, R _I = 1.5 Ω		12	24	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		13	26		
Fall Time	t _f			10	20		
Turn-On Delay Time	t _{d(on)}			9	18	ns	
Rise Time	t _r	- V _{DD} = 15 V, R _I = 1.5 Ω		9	18	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		14	28		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characterist	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			16		
Pulse Diode Forward Current	I _{SM}	-	1	1	32	A	
Body Diode Voltage	V _{SD}	I _S = 3 A, V _{GS} = 0 V	1	0.78	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		1	17	34	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	-		9.5	19	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		10		ns	
Reverse Recovery Rise Time	t _b	1		7			
lotes:			L	1	L		

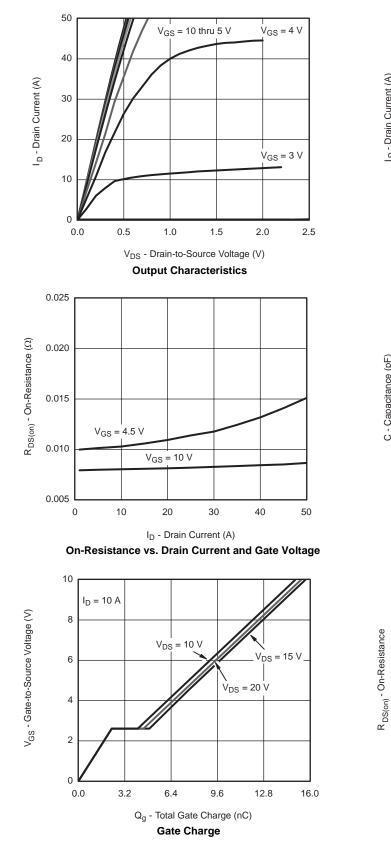
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

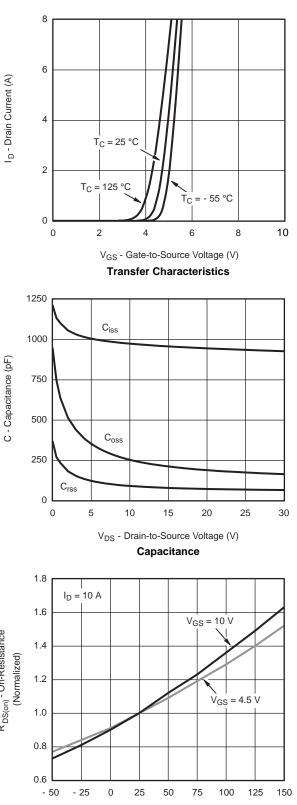
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi



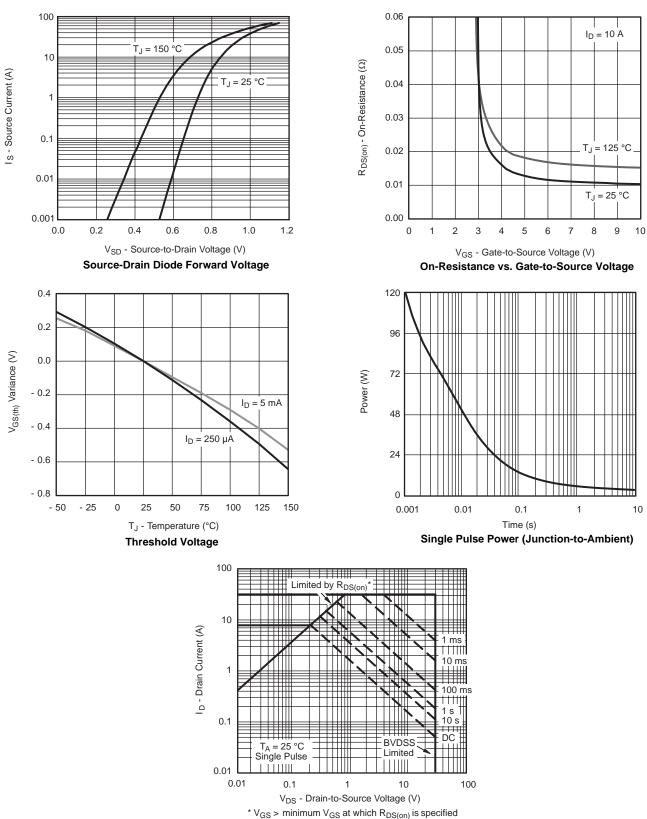




T_J - Junction Temperature (°C)

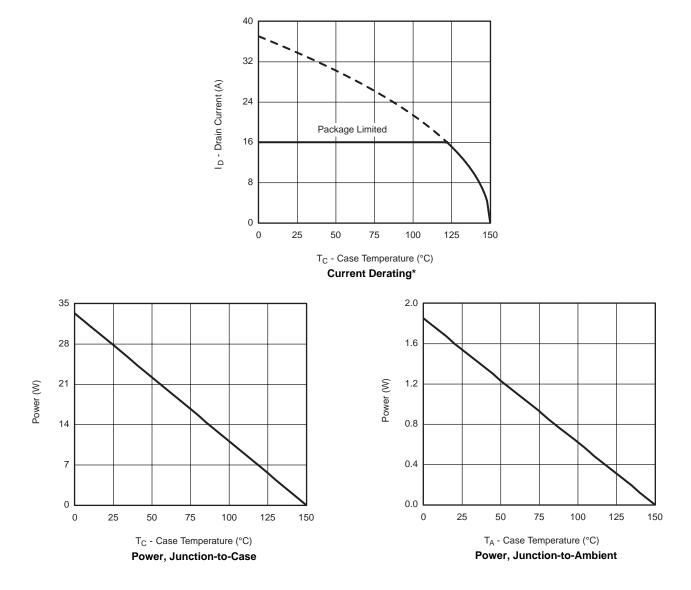
On-Resistance vs. Junction Temperature



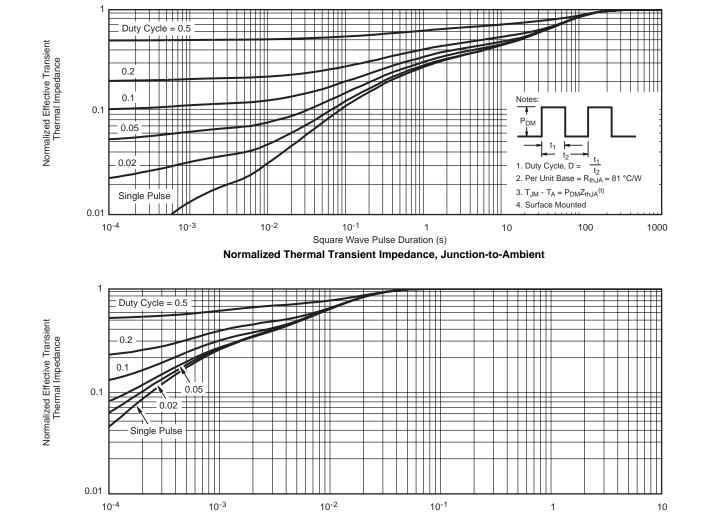


Safe Operating Area, Junction-to-Ambient





* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



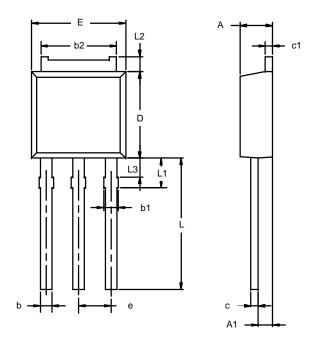
Square Wave Pulse Duration (s) Normalized Thermal Transient Impedance, Junction-to-Case

semi

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TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

	MILLIN	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
c1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28 BSC		0.090 BSC		
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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